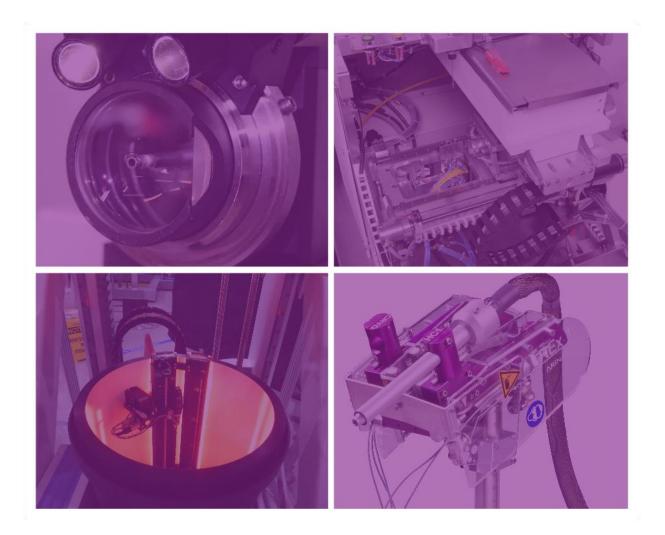
MD3-UP

Specification Overview



Release 03 June 19, 2019





1 Specifications

Orientation	
Ω axis	Vertical
Ω Scan axis	
Sphere of confusion	100 nm radius, @ 100 deg/s *)
(with SmartMagnet Nozzle)	100 mm radiad, @ 100 dog/0
Sphere of confusion	100 nm radius, @ 100 deg/s *)
(with MiniKappa Nozzle)	100 1111 144146, © 100 409/0
Max. Rotation speed	720 deg/s
Design angular resolution	0.1 mdeg (full step)
Static accuracy	Below ± 0.3 mdeg
Dynamic accuracy	Below ± 0.7 mdeg @10 deg/s
Sample alignment (AY,AZ): Raster / Grid scans axes	
Design resolution	5 nm
Range	AY: 108 mm
1.6.1.90	AZ: 6 mm
Static accuracy (on load)	Below ± 100 nm
Dynamic accuracy (on load)	Below ± 1µm @ 15 mm/s on AY
, , (,	Below ± 1µm @ 1 mm/s on AZ
Grid U-turn delay	< 300 ms @ 15 mm/s on AY
Centering table (CX,CY): Centering, Helical Scan axes	
Design resolution	5 nm
Range	CX, CY: 5 mm
Static accuracy (on load)	Below ± 100 nm
Dynamic accuracy (on load)	Below ± 1µm @ 0.8 mm/s on CX,CY
Beam aperture	
Diameter range	5 selectable diameters, Min: 5 µm
Resolution	16 nm
Repeatability	Below ± 1µm
Software	
User interface	JAVA Control application
Beamline software integration	Customizable (e.g. MXCube, Blu-Ice)
Multi-device servers	TINE, TANGO, EPICS
Sample changer robot	Robot hardware & software integration
Control features	Parallax-free sample visualization
	·
	semi-automatic sample centering
	4D Data collection strategies
	Advanced detector synchronization modes
	Selectable beam shaping tools



On Axis Video microscope	
Design resolution	0.16 µm/pixel
Resolving power	USAF target 1951, group 9.2 (575 lines per mm
	resolved)
Video Server bandwidth	≥ 20 FPS (depending on network)
Beamstop	
Movable beam-stop	
Distance to the sample	25 to 77 mm
	5 to 57 mm
Beamstop diameter	300 – 400 – 500 μm
Power Supply	
Voltage	110 VAC to 240 VAC
Frequency	50 to 60 Hz
Electric power	1000 W
Dimensions (W,H,D)	
Depth x Width x Height	225 x 600 x 600 mm ³
	(Support Feet can be added)
Weight	
Diffractometer only	90 kg

^{*)} with efficient vibration dumping and including measurement noise correction

2 Glossary

SOC: sphere that contains all the measured positions of the centered point during the spindle axis rotation.

Design Resolution: smallest increment that can be commanded to move and/or detect.

Accuracy: range of the deviation errors during a move, with coverage of 95.4% ($\pm 2\sigma$)

Static Accuracy: measure of in-position stability, i.e. Accuracy of the control system at null speed.

Dynamic Accuracy: Accuracy at a commanded speed.

Repeatability: worst spread in positioning error at any chosen target, calculated upon repeated moves, with a coverage of 95.4% ($\pm 2\sigma$)

Grid U-turn: the fastest Grid Scan (with potentially helical scan at the same time) method uses uninterrupted move of the sample to cover the full grid. The U-turn is a synchronized move of Alignment and Centering tables in order to change the move direction of the target without stopping the detector by mean of hardware synchronization.

Grid U-turn delay: time to reach a new line in the grid, .i.e the duration of the U-turn suspending the detector acquisition. At the beginning and at the end of the U-turn the AY motor speed is stable and the other axes are not moving.





ARINAX is a trademark of MAATEL SAS

Z.I. de Centr'Alp – 259 rue du Rocher de Lorzier – 38430 Moirans – France Siren 306 606 583 00038 – N°TVA FR92306606583 SAS capital of 1.000.000€ – RC Grenoble 76 B317

All information, pictures and drawings in this document are the property of Maatel SAS. Copying this document and distribute to others plus the use or communication of the contents thereof are forbidden without express authority. Contraveners are liable to the payment of damages. All rights reserved.